

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re: Park et al.

Serial No.: To Be Assigned

Filed: Concurrently Herewith

For: **METHODS OF FORMING SELF-ALIGNED CONTACT STRUCTURES IN SEMICONDUCTOR INTEGRATED CIRCUIT DEVICES**

September 5, 2003

Mail Stop PATENT APPLICATION

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

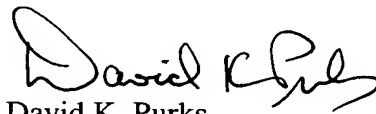
INFORMATION DISCLOSURE STATEMENT

Sir:

Attached is a list of documents on form PTO-1449 and PTO-892. Since the benefit of this application is claimed under 35 U.S.C. §120, no copies need to be furnished in accordance with 37 C.F.R. §1.98(d); however, copies will be furnished on request. It is requested that these documents be considered by the Examiner and officially made of record in accordance with the provisions of 37 C.F.R. §1.97 and Section 609 of the MPEP.

No fee is believed due. However, the Commissioner is hereby authorized to charge any deficiency or credit any overpayment to our Deposit Account No. 50-0220.

Respectfully submitted,



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Audra Wooten

Notice of References Cited	Application/Control No. 09/556,499	Applicant(s)/Patent Under Reexamination PARK ET AL.	
	Examiner Granvill D Lee, Jr	Art Unit 2825	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6160317	06-1999	Sun et al.	257/900
	B	US-6221714	06-1999	Jang	438/241
	C	US-5920763	08-1997	Schuegraf	438/3
	D	US-6259131	05-1998	Sung et al.	257/315
	E	US-5736442	09-1996	Mori	438/257
	F	US-6218689	08-1999	Chang et al.	257/288
	G	US-2001/0019866	02-2002	Jang	438/241
	H	US-6191444	09-1998	Clampitt et al.	257/315
	I	US-6403417	03-2002	Chien et al.	438/241
	J	US-6214739	02-1999	Haung et al.	438/709
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

FORM PTO-1449 U.S. Department of Commerce Patent and Trademark Office LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)				Attorney Docket Number 5649-821		Serial No. To Be Assigned	
				Applicants: Park et al.			
				Filing Date: Concurrently Herewith		Group	
U. S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
	1	5,897,372	04/27/99	Howard	438	637	
	2	5,766,992	06/16/98	Chou et al.	438	241	
	3	5,731,236	03/24/98	Chou et al.	438	253	
	4	5,597,763	01/28/97	Sim	437	195	
	5	5,591,670	01/07/97	Park et al.	437	187	
	6	5,567,989	10/22/96	Sim	257	774	
	7	5,506,157	04/09/96	Lee et al.	437	31	
	8	5,502,336	03/26/96	Park et al.	257	754	
	9	5,500,080	03/19/96	Choi	156	644.1	
	10	5,384,287	01/24/95	Fukase	437	228	
	11	4,966,868	10/30/90	Murali et al.	437	193	
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		Document Number	Date	Country	Class	Subclass	Translation Yes No
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							

 EXAMINER _____
 *EXAMINER _____

DATE CONSIDERED _____

Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.